

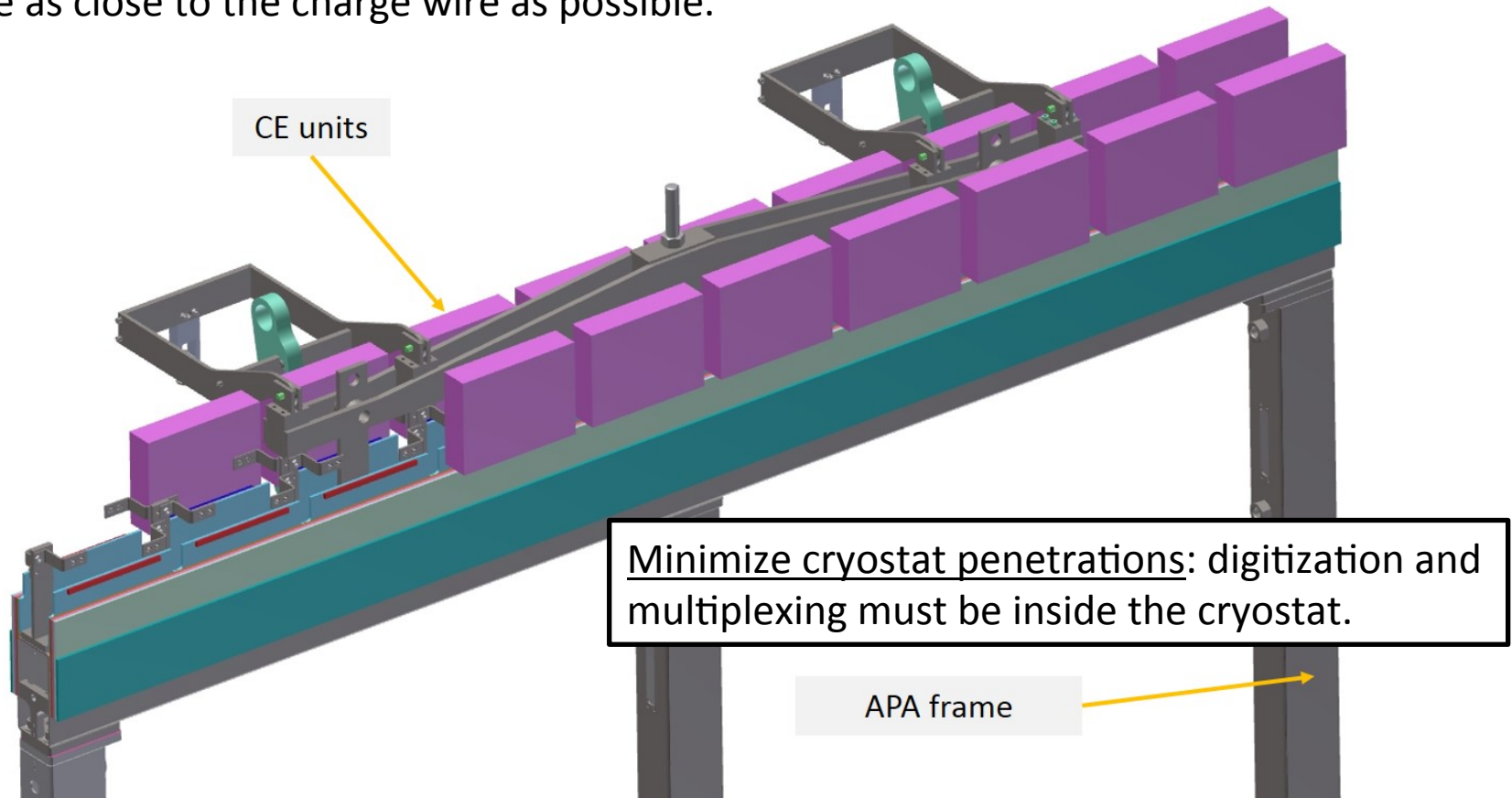
Cold Electronics Testing

Matthew Worcester (BNL)
for the CE design and testing team

10/4/16

Why Cold Electronics?

Minimize noise: front end amplification and filtering must be as close to the charge wire as possible.

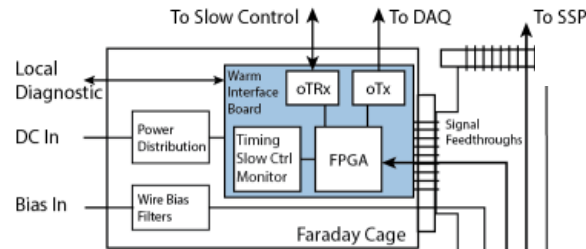


TPC Cold Electronics

ProtoDUNE shown – SBND has minor differences

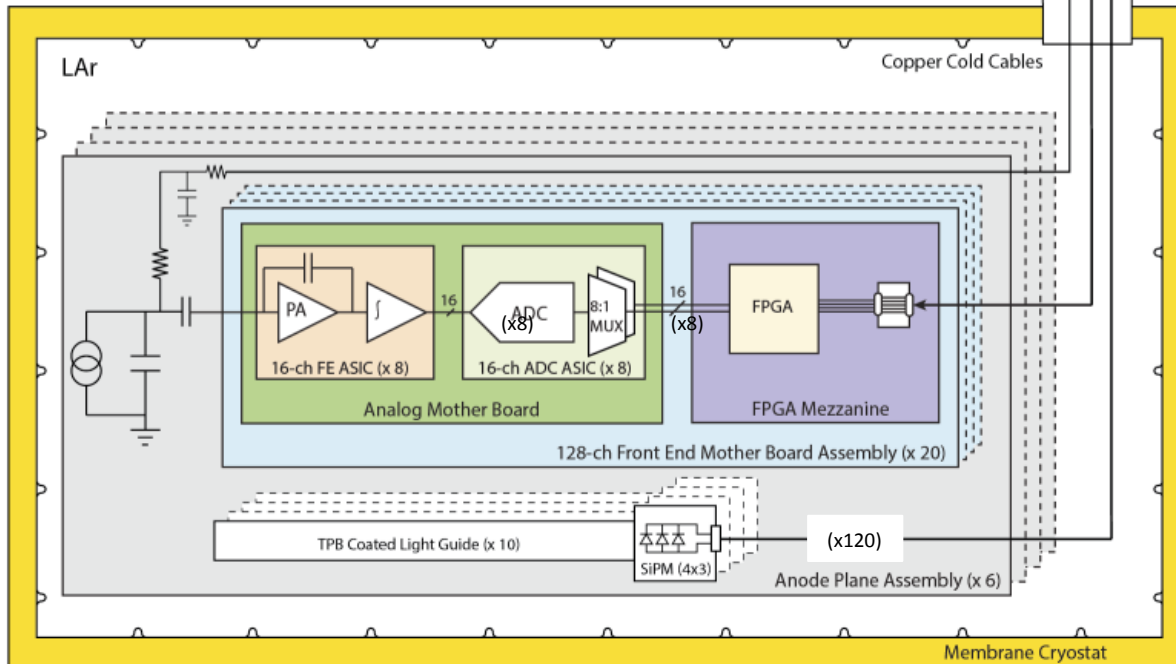
Warm electronics crate (WEC)

- Faraday cage w/only optical links
- 5/6 warm interface board/flange
- multiplex high-speed data to DAQ
- LV and clock/ctl fan-out to FEMB



Cryostat feed-through

- 6/4 warm flanges
- 20/24 FEMB/flange



Cold Copper cable

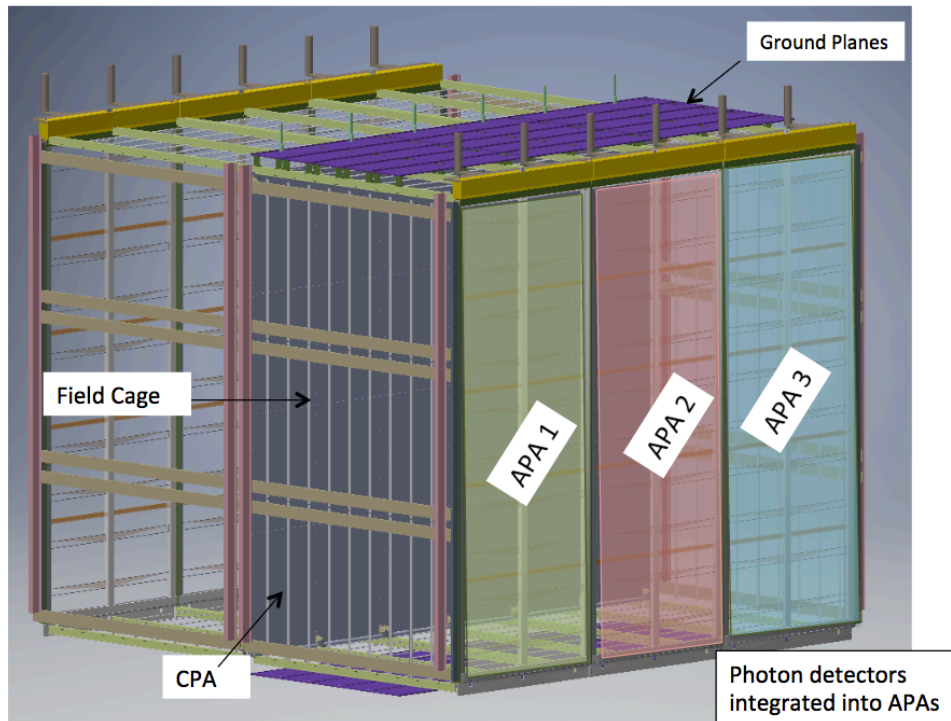
- x120 Samtec 26 AWG
- x88 3M 30 AWG (SBND)

Front-end Mother Board (FEMB) x120 (x88 SBND)

- FE charge amplifier with programmable gain/shaping for each channel
- 12-bit ADC at 2 MS/sec
- 4 x 1.2 Gbps links

What are all these things?

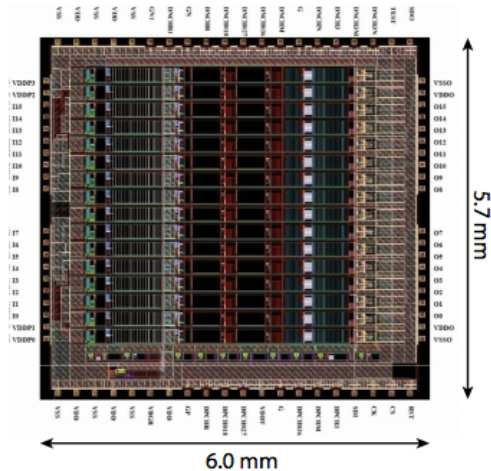
- Front-end (FE) and ADC ASICs
- FEMBs and cold cable
- Cryostat feed-through and flange
- Warm interface electronics



- ProtoDUNE single phase TPC
 - 6 Anode Plane Assemblies (APA) with 2,560 wires each
 - 20 FEMB/APA
 - 2 induction wire planes
 - 1 collection wire plane
 - 7m x 7.2m x 6m
 - 3.6m drift distance with 500V/cm field
- SBND TPC
 - 4 APA joined into 2 units with 5,632 wires each
 - 44 FEMB/joined APA
 - 2 induction wire planes
 - 1 collection wire plane
 - 4m x 5m x 4m
 - 2m drift distance

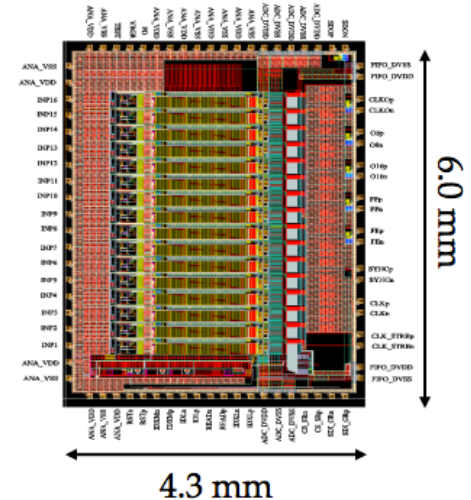
Cold ASICs

FE



- 16 programmable channels
- Charge amplifier, filter
- Adjustable gain
 - 4.7, 7.8, 14, 25 mV/fC
- Adjustable filter time constant
 - 0.5, 1, 2, 3 μ sec peaking time
- Selectable collection/non-collection wire mode
 - 200/900 mV baseline

ADC

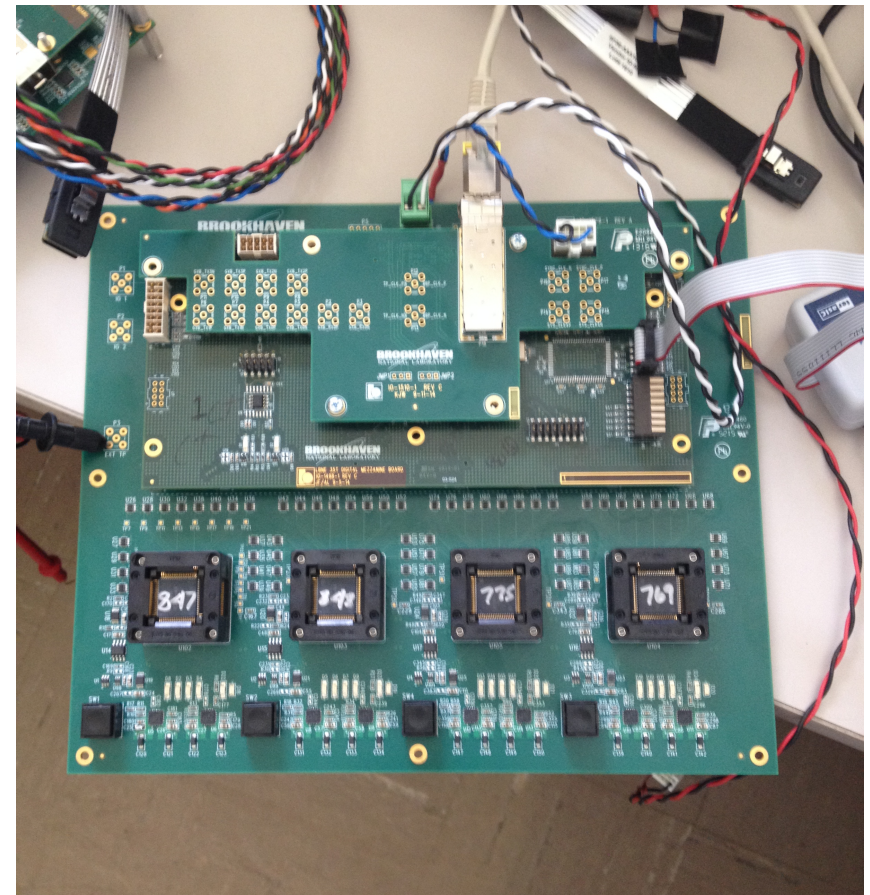
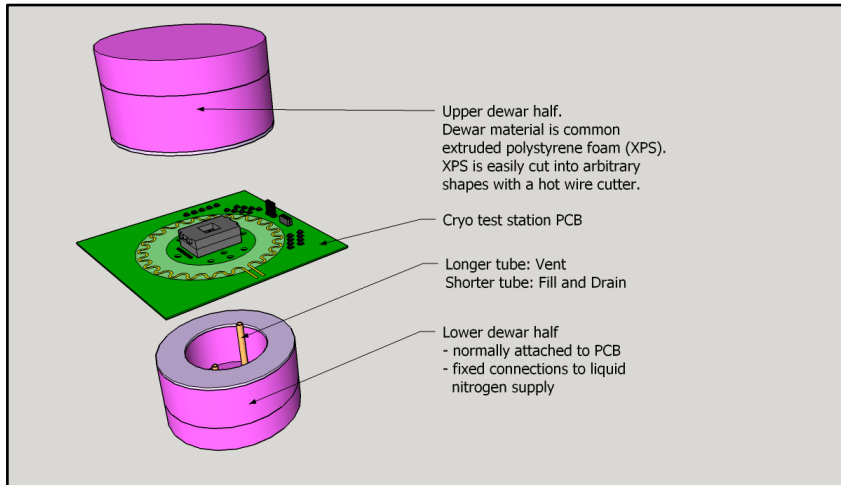


- 16 channels
- 0.2-1.6V input range
- 12-bit ADC sampling at up to 2 MHz
- FIFO 32 samples deep
- multiplexing by 8:1 or 16:1

Requirement: long lifetime (>25 yrs) and very low power consumption in cold.

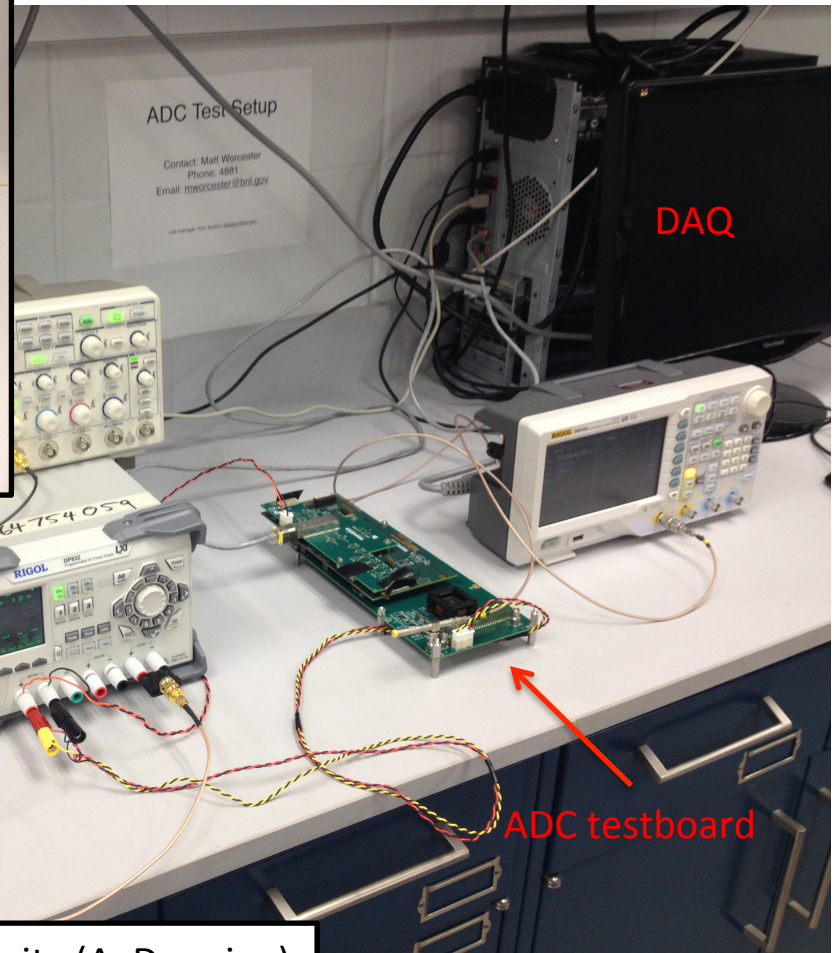
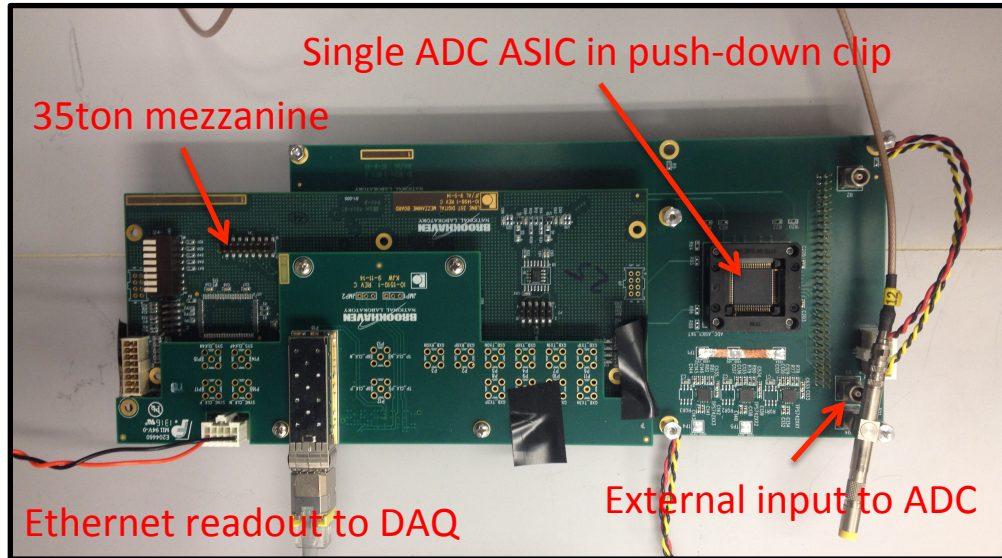
FE ASIC Testboard

- Prototype FE ASIC test board
 - Controlled by 35ton FPGA mezzanine
 - External DAC
 - 14-bit ADCs
- Read out each FE ASIC on all settings
 - Gain, peaking time, baseline, test capacitor enabled, AC/DC input
 - Also use internal pulser on current P1 version of FE ASICs
- Design for rapid-filling Dewar:

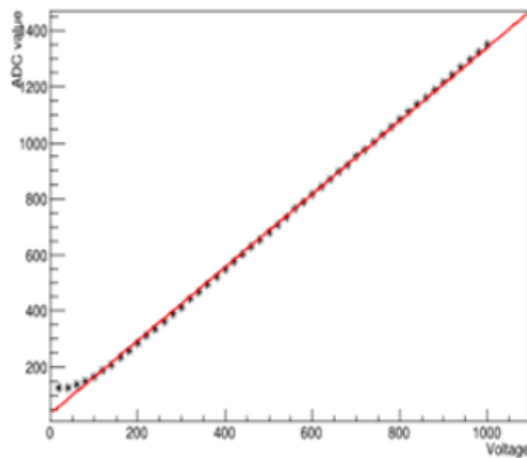


4 FE ASICs in push-down holding clips

ADC ASIC Teststand



ADC test analysis



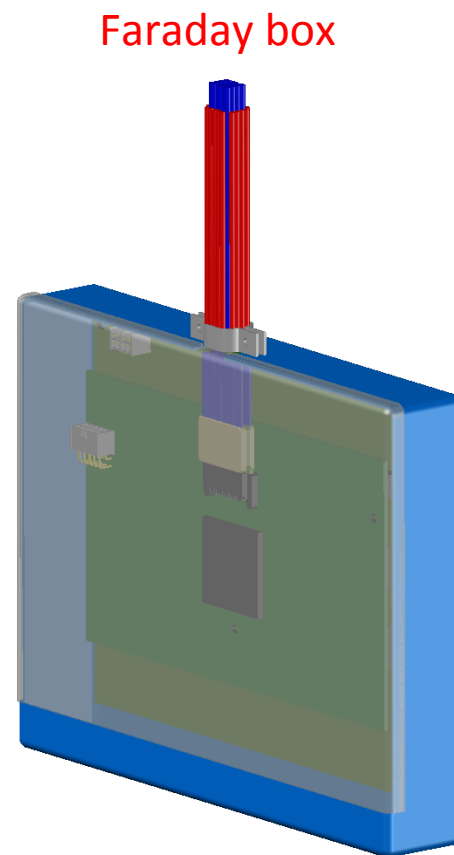
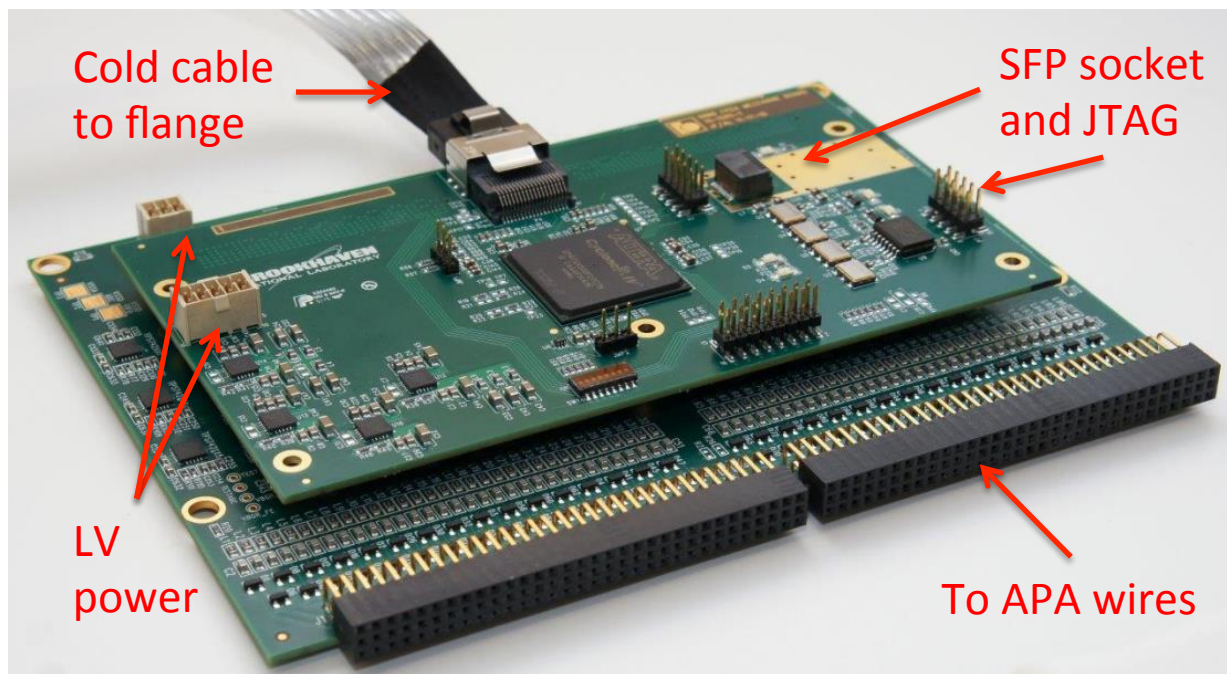
Crystal oscillator test jig

LV power

ADC testboard

Single channel ADC linearity (A. Depoian)

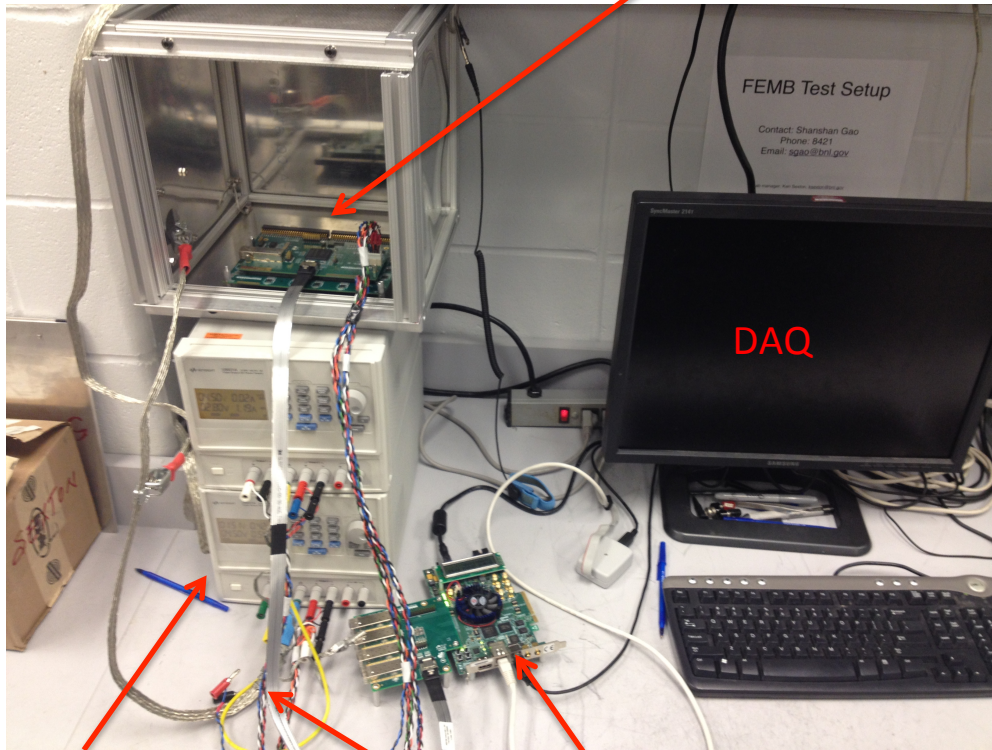
FEMB



- 128 channels of digitized TPC wire readout
 - 8 FE ASICs/8 ADC ASICs on the analog motherboard
 - Controlled by 2 COLDATA/1 FPGA on the mezzanine
- Mounted in modular Faraday box with built-in cable strain relief

FEMB Teststand

SBND FEMB in Faraday cage

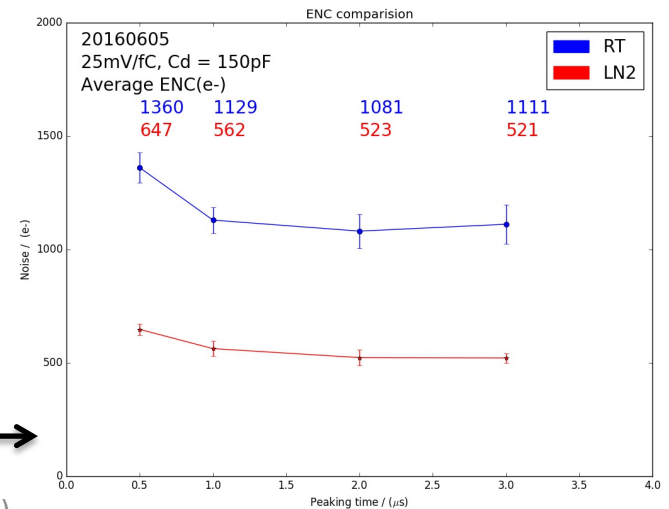
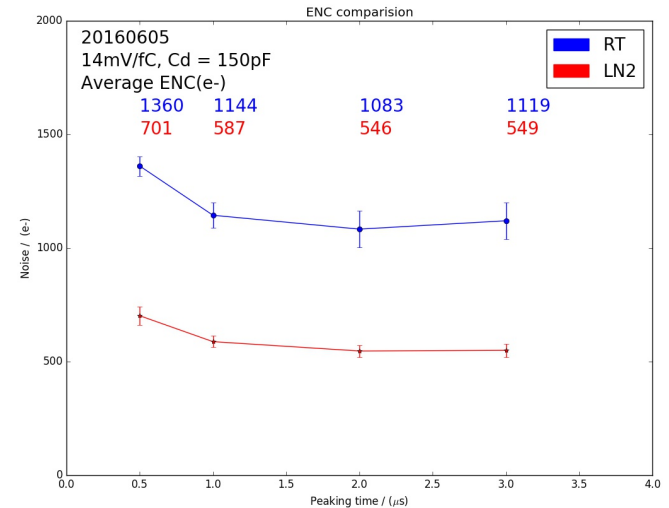


LV power

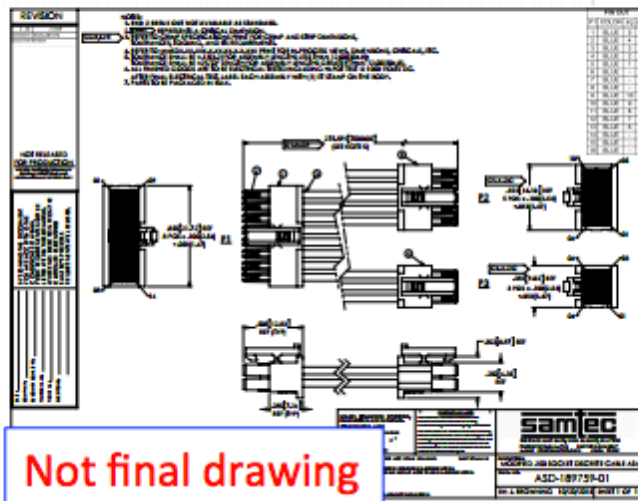
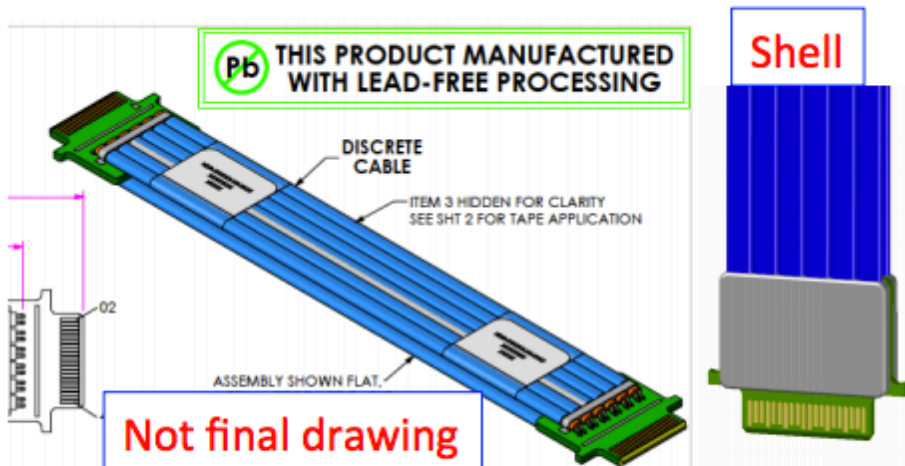
SBND data
cable

Warm electronics

Equivalent Noise Charge (ENC) vs peaking time



Cold Cable Bundles



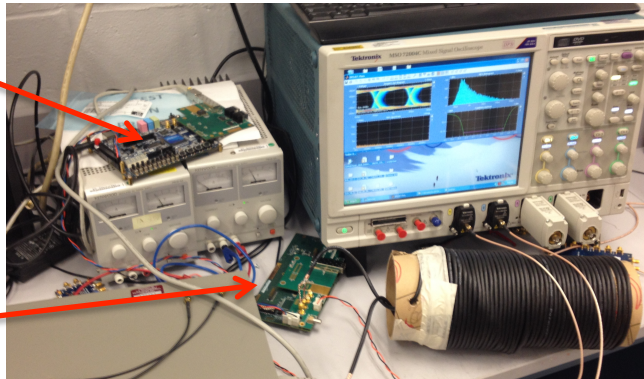
- 4 x 1.2 Gbps high-speed data links from each FEMB to the flange
- Clock, control IO, and FPGA programming links
- 12 pairs of copper twin-axial cable
 - ProtoDUNE: Samtec custom 26 AWG with HSEC08 connectors to both FEMB and flange
 - SBND: 3M mini-SAS with Molex connectors
- LV power: Samtec twisted pair copper wire (16 SBND, 18 ProtoDUNE)

FEMB 7m Cable	Net Name	# of Wires	R_RT [Ω]	R_LAr [Ω]	XSection [mm ²]
Analog Mother Board	FE-ANA-IN	3	0.078	0.025	1.554
	REGR_BIAS	1	0.233	0.074	0.518
FPGA Mezzanine	P1.5V	1	0.233	0.074	0.518
	P2.8V	1	0.233	0.074	0.518
	P3.6V	1	0.233	0.074	0.518
	BIAS	1	0.233	0.074	0.518
Summary		8	0.029	0.009	4.144

Cable Teststand

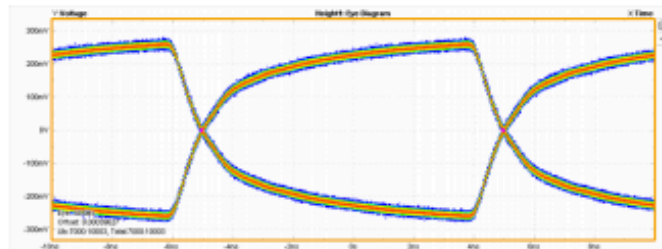
FPGA eval board

35ton FPGA mezzanine

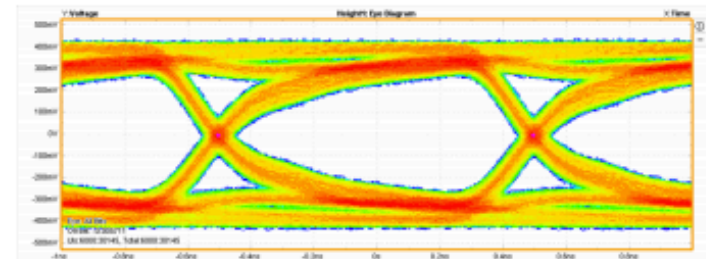


Tektronix oscilloscope

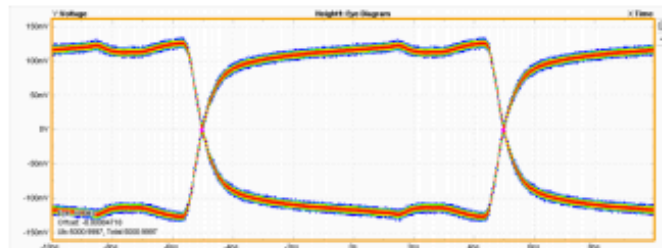
Cable!



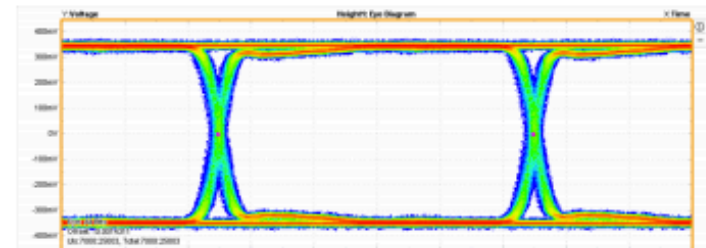
50MHz, **Samtec** 26AWG, 25m, RT
Height = 415mV, T_j = 180ps



1Gb/s, **Samtec** 26AWG, 7m, RT, w/o equalizer
Height = 429mV, T_j = 152ps

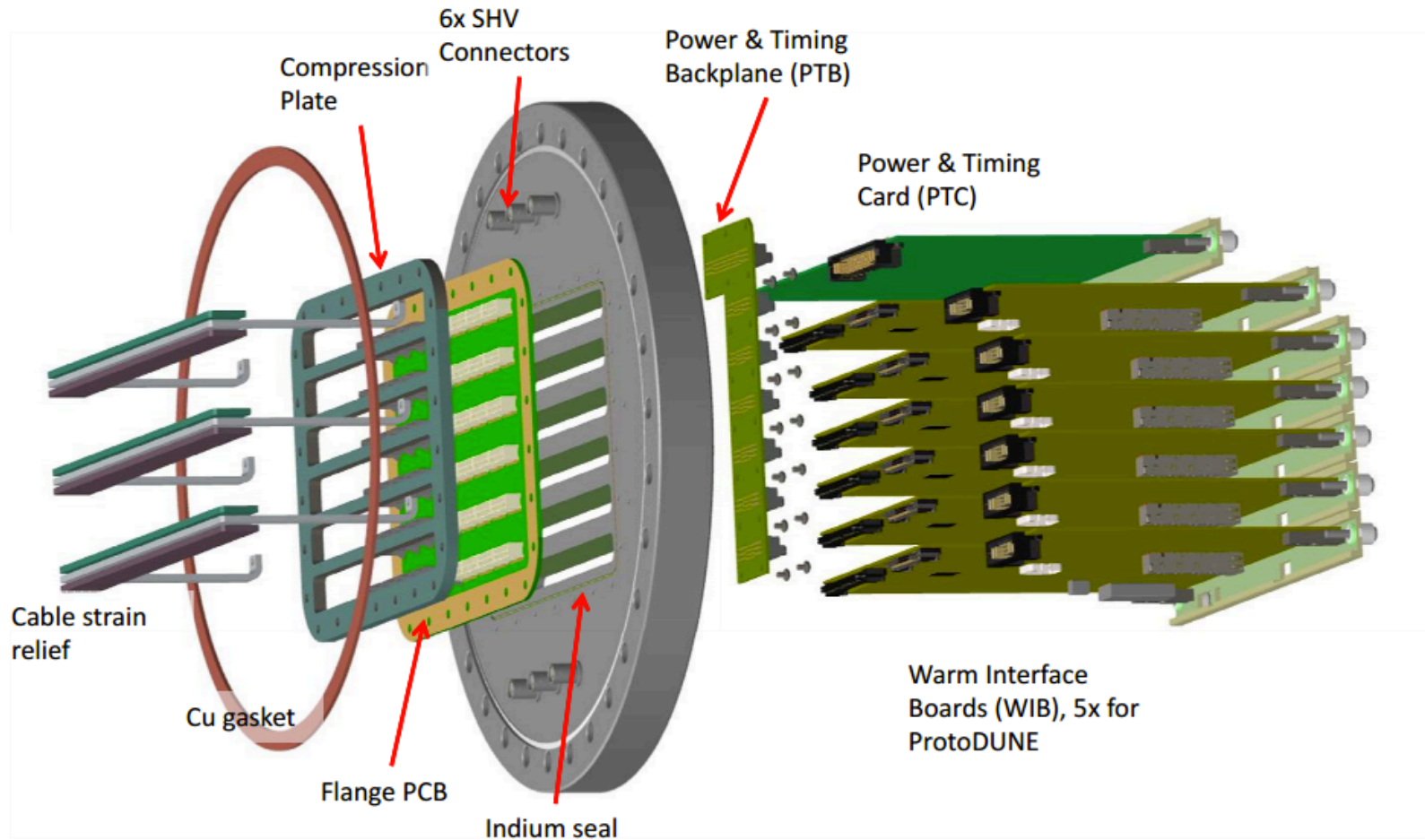


50MHz, **Gore** 24AWG, 25m, RT
Height = 218mV, T_j = 107ps



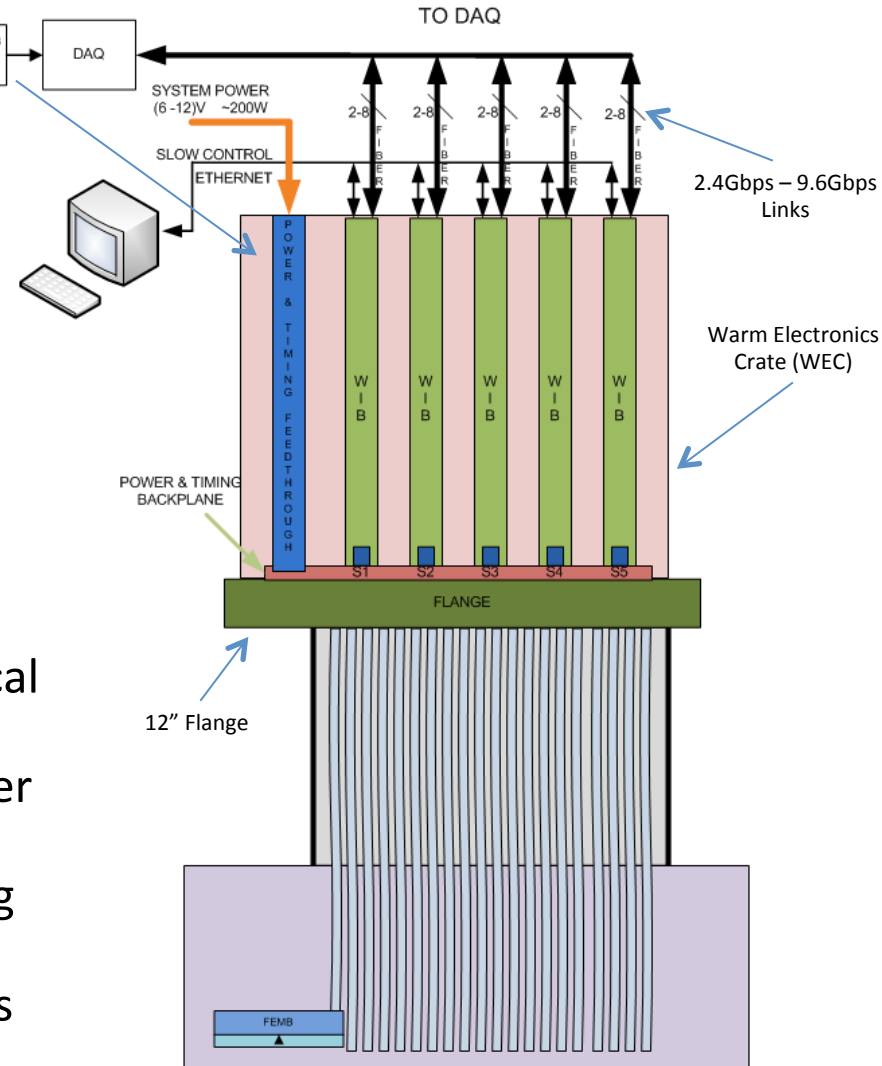
1Gb/s, **Samtec** 26AWG, 25m, RT, w. equalizer
Height = 628mV, T_j = 113ps

Cold Electronics Flange



Warm Interface Electronics

- One Warm Electronics Crate (WEC) per flange containing:
 - 5/6 Warm Interface Boards (WIB)
 - Each WIB controls up to 4 FEMBs
 - 1 Power and Timing Backplane (PTB)
 - 1 Power and Timing Card (PTC)
- Installed directly onto flange board
 - Receive high-speed data from cold cable
 - Send data to DAQ over 2-8 fiber optical links per WIB
 - Receive 50 clock and sync/control over fiber links to PTC or WIB
 - Interface to slow control system using fiber GIG-E
 - Manage power and control for FEMBs



Integration Teststand

- Full CE readout chain through the warm electronics
 - Use prototype FEMBs
 - Dewar and other cryogenic infrastructure
 - Test warm components
 - Flange
 - Warm interface electronics
 - Cable and connectors
- Goal: full validation of CE through the warm interface
 - Use FELIX PCIe DAQ
 - 10 Gbps Ethernet readout



MicroBooNE prototype integration teststand
(Hucheng Chen)

Lab 1-216

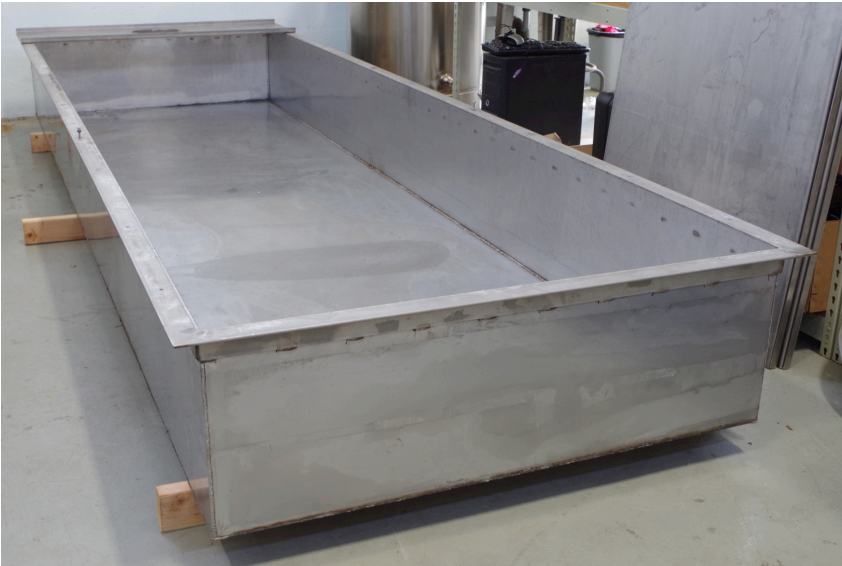
- Joint SBND/DUNE testing lab for cold electronics
- Goal: validate all cold electronics for SBND and ProtoDUNE
 - Everything tested here before shipping to CERN or FNAL
- Develop teststands and test procedures for:
 - FE and ADC ASICs
 - Front end motherboards (FEMB)
 - Cryostat feed-through and warm electronics
- Joint effort between BNL and several others: Fermilab, MSU, UTA, Penn



Cold box with 40% APA

Integrated APA+CE+electronics feed-through teststand in the BNL Physics high-bay

- Cold box to submerge FEMB in LN2 (77K)
- Read out via CE flange with WIB/crate
- Bias wires to nominal bias HV



40% prototype APA from PSL with up to 8 FEMB: adapters to CR board with onboard wire bias RC filters already installed